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# N-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A) <sup>a, e</sup>	Q <sub>g</sub> (Typ.)			
30	0.0014 at V <sub>GS</sub> = 10 V	135	82 nC			
30	$0.0020$ at $V_{GS} = 4.5 \text{ V}$	110	02110			

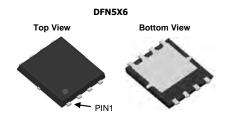
#### **FEATURES**

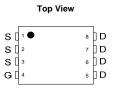
- **DT-Trench Power MOSFET**
- 100 %  $R_g$  and UIS Tested

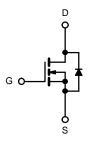


#### **APPLICATIONS**

- OR-ing
- Server







N-Channel MOSFET

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	30	V	
Gate-Source Voltage	$V_{GS}$	± 20	v	
	T <sub>C</sub> = 25 °C		135 <sup>a, e</sup>	
Continuous Drain Current (T <sub>.I</sub> = 175 °C)	T <sub>C</sub> = 70 °C		100 <sup>e</sup>	
Continuous Diam Current (1) = 173 C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	38 <sup>b, c</sup>	A
	T <sub>A</sub> = 70 °C		32 <sup>b, c</sup>	^
Pulsed Drain Current	I <sub>DM</sub>	390		
Avalanche Current Pulse	L = 0.1 mH	I <sub>AS</sub>	36	
Single Pulse Avalanche Energy	L = 0.1 IIII	E <sub>AS</sub>	650	mJ
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	I <sub>S</sub>	135 <sup>a, e</sup>	A
Continuous Source-Diam Diode Current	T <sub>A</sub> = 25 °C	'S	9.3 <sup>b, c</sup>	^
	T <sub>C</sub> = 25 °C		310 <sup>a</sup>	
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	P <sub>D</sub>	212	W
	T <sub>A</sub> = 25 °C	rD	4.25 <sup>b, c</sup>	VV
	T <sub>A</sub> = 70 °C		2.98 <sup>b, c</sup>	
Operating Junction and Storage Temperature Ra	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS							
Parameter	Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 s	R <sub>thJA</sub>	5	6.5	°C/W		
Maximum Junction-to-Case	Steady State	R <sub>thJC</sub>	0.5	0.6	C/VV		

- a. Based on T<sub>C</sub> = 25 °C. b. Surface mounted on 1" x 1" FR4 board.
- d. Maximum under steady state conditions is 90 °C/W.
- e. Calculated based on maximum junction temperature. Package limitation current is 90 A.



Parameter	Symbol	Test Conditions	Min .	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			>
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = 250 μA		35		mV/°C
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	10 = 200 μΑ		- 7.5		IIIV/ C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1		3	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V			1	μA
Zero Gate voltage Drain Current		V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			10	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	135			Α
D : 0	В	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 40 A		0.0014	0.0018	Ω
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 4.5 \text{ V}, I_D = 40 \text{ A}$		0.0020	0.0025	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 40 A		160		S
Dynamic <sup>b</sup>						
Input Capacitance	C <sub>iss</sub>			3890		pF
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ = 12.5 V, $V_{GS}$ = 0 V, f = 1 MHz		1996		
Reverse Transfer Capacitance	C <sub>rss</sub>			970		
Total Gate Charge	Qg	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 40 \text{ A}$		171	257	nC
				81.5	123	
Gate-Source Charge	$Q_{gs}$	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$		34		
Gate-Drain Charge	Q <sub>gd</sub>			29		
Gate Resistance	R <sub>g</sub>	f = 1 MHz		1.4	2.1	Ω
Turn-On Delay Time	t <sub>d(on)</sub>			18	27	
Rise Time	t <sub>r</sub>	$V_{DD} = 15 \text{ V}, R_L = 0.555 \Omega I_D$		11	17	ns
Turn-Off Delay Time	t <sub>d(off)</sub>	$\cong$ 40 A, V <sub>GEN</sub> = 10 V, R <sub>g</sub> = 1 $\Omega$		70	105	
Fall Time	t <sub>f</sub>			10	15	
Turn-On Delay Time	t <sub>d(on)</sub>			55	83	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_L$ = 0.625 $\Omega$		180	270	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 40A$ , $V_{GEN} = 4.5$ V, $R_g = 1$ $\Omega$		55	83	
Fall Time	t <sub>f</sub>			12	18	
<b>Drain-Source Body Diode Characteristic</b>	s					
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			135	۸
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				390	A
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 22 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			52	78	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	1 20 A di/dt 400 A/:- T 05 00		70.2	105	nC
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		27		
Reverse Recovery Rise Time	t <sub>b</sub>			25		ns

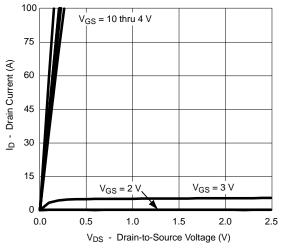
#### Notes:

- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

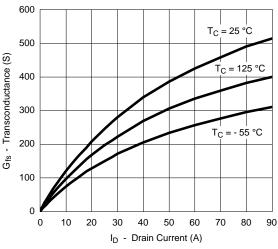
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



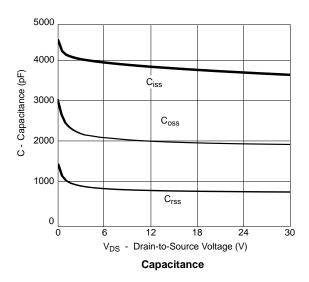
### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

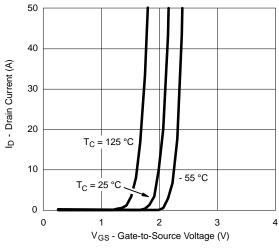


#### **Output Characteristics**

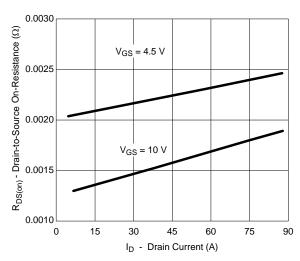


Transconductance

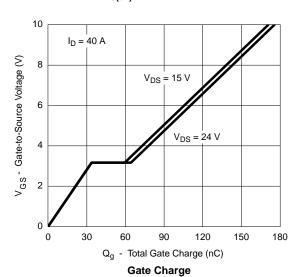




Transfer Characteristics

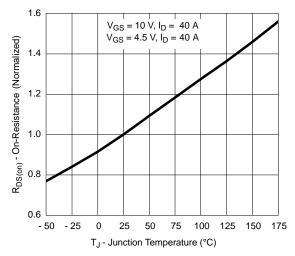


R<sub>DS(on)</sub> vs. Drain Current

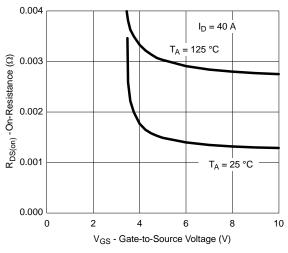




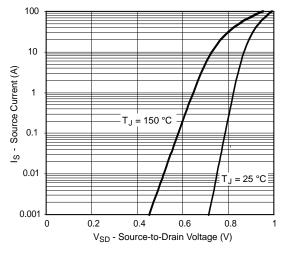
#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



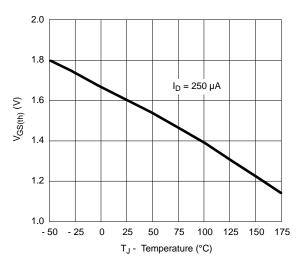
#### On-Resistance vs. Junction Temperature



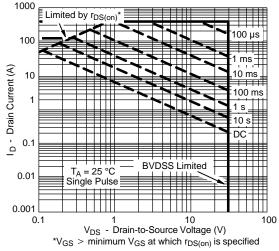
 $R_{DS(on)}$  vs.  $V_{GS}$  vs. Temperature



Forward Diode Voltage vs. Temperature



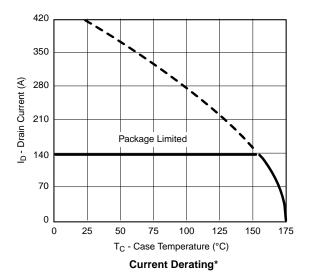
Threshold Voltage

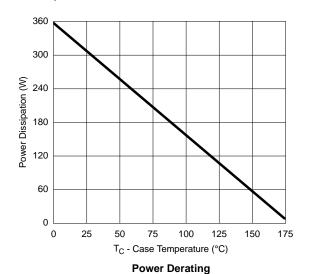


Safe Operating Area, Junction-to-Ambient

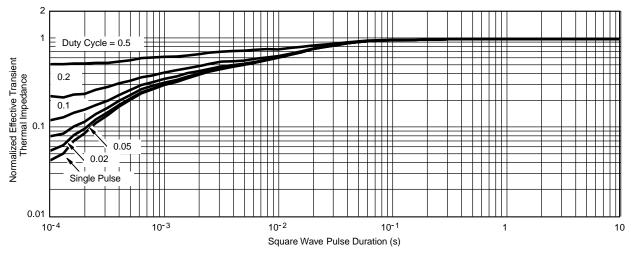


#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





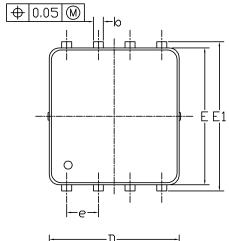
\* The power dissipation  $P_D$  is based on  $T_{J(max)} = 175$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

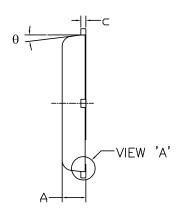


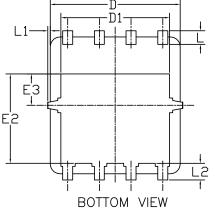
Normalized Thermal Transient Impedance, Junction-to-Case

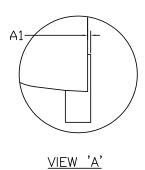






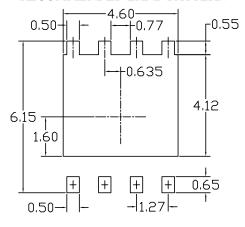






(SCALE 5:1)

RECOMMENDED LAND PATTERN



SYMBOLS DIMENSIONS IN MILLIN			METERS DIMENSIONS IN INCHES		CHES		
3 I MBOLS	MIN	NOM	MAX	MIN	NOM	MAX	
A	0.85	0. 95	1.00	0.033	0.037	0.039	
A1	0.00		0.05	0.000		0.002	
b	0.30	0.40	0.50	0.012	0.016	0.020	
С	0. 15	0. 20	0. 25	0.006	0.008	0.010	
D	4. 80	5. 20	5. 30	0. 201	0. 205	0. 209	
D1	4. 25	4. 35	4. 45	0. 167	0.171	0. 175	
Е	5. 45	5. 55	5. 65	0. 215	0. 219	0. 222	
E1	5. 95	6.05	6. 15	0. 234	0. 238	0. 242	
E2	3. 525	3. 625	3. 725	0. 139	0. 143	0. 147	
E3	1. 175	1. 275	1. 375	0.046	0.050	0.054	
e	1. 27 BSC			0.050 BSC			
L	0.45	0. 55	0.65	0.018	0.022	0.026	
L1	0		0. 15	0		0.006	
L2	0.68 REF			0. 027 REF			
θ	0°		10°	0°		10°	

#### **NOTE**

**Din-Tek** 

SEMICONDUCTOR

- 1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS. MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
- 2. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.

UNIT: mm





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